@PFDesktop\::ODMA/MHODMA/iManage;397072;1 NSP/KTS/dab 07/15/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic	ant:	Duy-Phach Vu, Brenda D. Dingle, Jason E. Dingle and Ngwe Cheong
	uation Applica	ontion 09/465,140
Filed:		December 16, 1999
Title:		METHOD OF FORMING AN ACTIVE MATRIX DISPLAY
		Date: 07-15-03
		Date: <u>07-/5-03</u> EXPRESS MAIL LABEL NO. <u>E W 3 /49356/34</u> S
	<u> </u>	
		INFORMATION DISCLOSURE STATEMENT
P.O. Bo	ssioner for Pate ox 1450 dria, VA 22313	
Sir:		
This In	under 37 CFR	closure Statement is submitted: 2.1.129(a), or ssion after Final Rejection)
[X]	stage in an internation	the following time periods: three months of filing national application (other than a CPA) or date of entry of the national application; or before the mailing date of a first office action on the merits in a non-provisional application, including a por Continued Examination).
[]	under 37 CFR	1.97(c) together with either:
	[] a State	ement under 37 CFR 1.97(e), as checked below, or
	• -	97(b) time period, but before final action or notice of allowance, whichever occurs first)
[]	under 37 CFR	1.97(d) together with:
	[] a State	ement under 37 CFR 1.97(e), as checked below, and
		0.00 fee under 37 CFR 1.17(p), or on or notice of allowance, whichever occurs first, but on or before payment of the issue fee)
[]	under 37 CFR Applicant rec (Filed after payment	quests that the IDS and cited reference(s) be placed in the application filewrapper.

Staten	nent Un	<u>der 37 (</u>	CFR 1.97(e)		
[]	any co	mmuni	nformation contained in this Information Disclosure Statement was first cited in cation from a foreign patent office in a counterpart foreign application not more nths prior to the filing of this Information Disclosure Statement; or		
[]	comm knowl in the	unication edge of informa	formation contained in this Information Disclosure Statement was cited in a on from a foreign patent office in a counterpart foreign application, and, to the the undersigned, after making reasonable inquiry, no item of information contained tion disclosure statement was known to any individual designated in 37 CFR than three months prior to the filing of this Information Disclosure Statement.		
Staten	nent Un	der 37 ((Patent Term Adjustment) Applies to original applications (other than design) filed on or after May 29, 2000		
[]	comm was no	unication ot receiv	Information contained in the Information Disclosure Statement was cited in a son from a foreign patent office in a counterpart application and this communication red by any individual designated in § 1.56(c) more than thirty days prior to the aformation Disclosure Statement.		
[X]	Enclosed herewith is form PTO-1449:				
	[]	Copies	s of the cited references are enclosed.		
	[X]	Applic	s of cited references are enclosed except those entered in prior application, U.S. ation No. 09/465,140, to which priority under 35 U.S.C. 120 is claimed. The application contains copies of the cited references.		
	[]	The list	sted references were cited in the enclosed International Search Report in a rpart foreign application.		
	[]	The "c	oncise explanation" requirement (non-English references) for reference(s) [37 CFR 1.98(a)(3) is satisfied by:		
		[]	the explanation provided on the attached sheet.		
		[]	the explanation provided in the Specification.		
		[]	submission of the enclosed International Search Report.		
		[]	submission of the enclosed English-language version of a foreign Search Report and/or foreign Office Action.		
		[]	the enclosed English language abstract.		

[]	App	licant requests that the following r	non-published pending appli	cations be considered:
Examiner's Initials	i			
-		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: []
		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: []
		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: []
		Examiner	Date	_
	[]	A copy of each above-cited app	plication, including the curre	nt claims, is enclosed.
	[]	A copy of each above-cited app those entered in prior application 35 U.S.C. 120 is claimed.	olication, including the curre on, U.S. Application No. [nt claims, is enclosed, except], to which priority under
		er is requested to return a copy of ere considered with the next offic		plications indicating which
It is re	queste	ed that the information disclosed h	erein be made of record in the	nis application.
Metho	d of p	ayment:		
[]		eck for the fee noted above is encl mpanying Reply. A copy of this S		cluded in the check with the
[]	Pleas	se charge Deposit Account 08-038 osed.	0 in the amount of \$[]	. A copy of this Statement is
[X]	Pleas	se charge any deficiency in fees an	d credit any overpayment to	Deposit Account 08-0380.
		R	Respectfully submitted,	
		H	IAMILTON, BROOK, SMI	TH & REYNOLDS, P.C.
			Kevin T. Shaughnessy Registration No.: 51,014 Telephone: (978) 341-0036 Facsimile: (978) 341-0136	•

Concord, MA 01742-9133 Dated: 7/15/03

@PFDesktop\::ODMA/MHODMA/iManage;397082;1 CONTINUATION OF APPLICATION PTO-1449 REPRODUCED ATTORNEY DOCKET NO. 0717.1063-007 No. 09/465,140 INFORMATION DISCLOSURE CITATION IN AN APPLICATION APPLICANT Duy-Phach Vu, et al. July 15, 2003 FILING DATE CONFIRMATION NO. GROUP (Use several sheets if necessary)

		U.S.	PATENT DOCUMENTS	
EXAM- INER INI- TIAL	REF. NO.	DOCUMENT NUMBER	ISSUE DATE / PUBLICATION DATE	NAME
	AA	4,575,854	03-11-86	Martin
	AB	4,727,047	02-23-88	Bozler, et al.
	AC	4,774,205	09-27-88	Choi, et al.
	AD	4,769,680	09-06-88	Resor, III, et al.
	AE	4,808,983	02-28-89	Benjamin, et al.
	AF	4,838,654	06-13-89	Hamaguchi, et al.
	AG	4,846,931	07-11-89	Gmitter, et al.
	АН	4,855,255	08-08-89	Goodhue
	AI	4,863,877	09-05-89	Fan, et al.
	AJ	4,870,475	09-26-89	Endo, et al.
	AK	4,883,561	11-28-89	Gmitter, et al.
	AA2	4,935,792	06-19-90	Tanaka, et al.
	AB2	4,961,629	10-09-90	Kato
	AC2	4,965,565	10-23-90	Noguchi
	AD2	4,979,002	12-18-90	Pankove
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	AF2	5,073,806	12-17-91	Idei
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	AI2	5,166,816	11-24-92	Kaneko, et al.
	AJ2	5,184,235	02-02-93	Sukegawa
	AK2	5,191,453	03-02-93	Okumura
	AA3	5,206,749	04-27-93	Zavracky, et al.
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	AC3	5,317,433	05-31-94	Miyawaki, et al.

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INFORMATION DISCLOSURE CITATION	0717.1063-007		140. 09/403,140	
IN AN APPLICATION July 15, 2003	APPLICANT Duy-Phach Vu, et al.			
(Use several sheets if necessary)	FILING DATE		CONFIRMATION NO.	GROUP

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	AD3	5,347,154	09-13-94	Takahashi, et al.		
	AE3	5,362,671	11-08-94	Zavracky, et al.		
	AF3	5,377,031	12-27-94	Vu, et al.		
	AG3	5,499,124	03-12-96	Vu, et al.		
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	AI3	5,245,452	09-14-93	Nakamura, et al.		
	AJ3	5,757,445	06-26-98	Vu, et al.		
	AK3	5,164,853	11-17-92	Shimazaki		
	AA4	3,862,360	01-21-75	Dill, et al.		
	AB4	4,094,058	06-13-76	Yasutake, et al.		
	AC4	5,108,843	04-28-92	Ohtaka, e4t al.		
	AD4	4,998,152	03-05-91	Batey, et al.		
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July 15, 2003

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ATTORNEY	DOCKET	NO.
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CONTINUATION OF APPLICATION No. 09/465,140

APPLICANT

Duy-Phach Vu, et al.

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	T	FOREIGN PATENT I	DOCUMENTS	<u> </u>
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
 AL	1-195421	08 Jul 89	Japan (English Abstract)	
AM	2 058 427	04 Sep 80	Great Britain	
AN	63-101831	06 May 88	Japan	
AO	63-55529	10 Mar 88	Japan	
AP	64-38727	09 Feb 89	Japan	
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AR	Akiyama, M., et al., "Growth of GaAs on Si and Its Application to Fets and LEDs.", Nat. Res. Soc. Symp. Proc., 67:53-64 (1986).				
AS	Allen, et al., "Characterization of Isolated Silicon Epitaxy Material", SPIE, Vol. 945 - Advanced Processing of Semiconductor Devices II (3/17-3/18, 1988).				
AT	Conference Record of the 1991 International Display Research Conference, October 15-17, 1991, IEEE.				
AU	Fan, et al., "Lateral Epitaxy by Seeded Solidification for Growth of Crystal Si Films on Insulators", <u>Appl. Phys. Lett.</u> , 38, 365, 3-1-81.				
AV	McClelland, et al., "A Technique for Producing Epitaxial Films on Reusable Substrates", Appl. Phys. Lett., 37, 560, 9-15-80.				
AW	McDaniel, D.L., et al., "Vertical Cavity Surface-Emitting Semi-Conductor Laser with CW Injection Laser Pumping", IEEE Photon Technol. Lett., March 23, 1990.				
AX	Milnes, A.G., "Semiconductor Heterojunction Topics: Introduction and Overview", Solid State Electronics, Vol. 29, 2:99-121 (1986).				
AY	Turner, G., et al., "High-Speed Photoconductive Detectors Fabricated in Heteroepitaxial GaAs Layers", Mat. Res. Soc. Symp. Proc., 67:181188 (1986).				
AZ	Weber, J.P., et al., "Effects of Layer Thickness Variations on Vertical Cavity Surface-Emitting DBR Semiconductor Lasers", <u>IEEE Photon Tech. Ltr.</u> , March 23, 1990.				
AR2	Yablonovitch, et al., "Extreme Selectivity in the Lift-Off of Epitaxial GaAs Films", Appl. Phys. Lett., 51, 2222 12-28-87.				
AS2	Sumiyoshi, et al., Device Layer Transferred Poly Si TFT Array for High Resolution Liquid Crystal Projector", IEEE, 7.3.1-7.3.4, 1989.				
AT2	Y. Hayashi, et al., "A New Three Dimensional IC Fabrication Technology, Stacking This Film Dual-CMOS Layers", IEEE IDEM, pps. 657-660, 1991.				
AU2	"3-D Chip on Chip Stacking", Semiconductor International, December 1991.				

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IN AN AFFLICATION	APPLICANT		
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	AV2	Matsumoto, et al., "Liquid Crystal Displays (LCDs)", Electronic Display Devices, (John Wiley and Sons) pps. 29-84.			
	AW2				
	AX2				
	AY2				
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